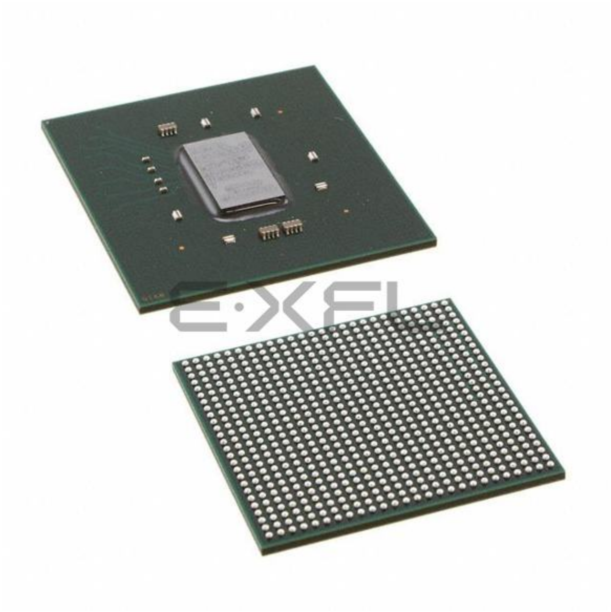

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details	
Product Status	Active
Number of LABs/CLBs	25475
Number of Logic Elements/Cells	326080
Total RAM Bits	16404480
Number of I/O	400
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	676-BBGA, FCBGA
Supplier Device Package	676-FCBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7k325t-2ffg676i

Table 2: Recommended Operating Conditions [(1)](#) *(Cont'd)*

Symbol	Description	Min	Typ	Max	Units
$V_{MGTAVTTRCAL}$(8)	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	1.17	1.2	1.23	V
XADC					
V_{CCADC}	XADC supply relative to GNDADC	1.71	1.80	1.89	V
V_{REFP}	Externally supplied reference voltage	1.20	1.25	1.30	V
Temperature					
T_j	Junction temperature operating range for commercial (C) temperature devices	0	–	85	°C
	Junction temperature operating range for extended (E) temperature devices	0	–	100	°C
	Junction temperature operating range for industrial (I) temperature devices	–40	–	100	°C

Notes:

1. All voltages are relative to ground.
2. V_{CCINT} and V_{CCBRAM} should be connected to the same supply.
3. Configuration data is retained even if V_{CCO} drops to 0V.
4. Includes V_{CCO} of 1.2V, 1.5V, 1.8V, 2.5V, and 3.3V.
5. The lower absolute voltage specification always applies.
6. A total of 200 mA per bank should not be exceeded.
7. V_{CCBATT} is required only when using bitstream encryption. If battery is not used, connect V_{CCBATT} to either ground or V_{CCAUX}.
8. Each voltage listed requires the filter circuit described in UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide*.
9. For data rates ≤ 10.3125 Gb/s, $V_{MGTAVCC}$ should be 1.0V ±3% for lower power consumption.
10. For lower power consumption, $V_{MGTAVCC}$ should be 1.0V ±3% over the entire CPLL frequency range.

Table 3: DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Min	Typ(1)	Max	Units
V_{DRINT}	Data retention V_{CCINT} voltage (below which configuration data might be lost)	0.75	–	–	V
V_{DRI}	Data retention V_{CCAUX} voltage (below which configuration data might be lost)	1.5	–	–	V
I_{REF}	V_{REF} leakage current per pin	–	–	15	µA
I_L	Input or output leakage current per pin (sample-tested)	–	–	15	µA
C_{IN}(2)	Die input capacitance at the pad	–	–	8	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 3.3V	90	–	330	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 2.5V	68	–	250	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.8V	34	–	220	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.5V	23	–	150	µA
	Pad pull-up (when selected) @ V_{IN} = 0V, V_{CCO} = 1.2V	12	–	120	µA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 3.3V	68	–	330	µA
	Pad pull-down (when selected) @ V_{IN} = 1.8V	45	–	180	µA
I_{CCADC}	Analog supply current, analog circuits in powered up state	–	–	25	mA
I_{BATT}(3)	Battery supply current	–	–	150	nA

Table 6: **Typical Quiescent Supply Current *(Cont'd)***

Symbol	**Description**	**Device**	**Speed Grade**				**Units**
			1.0V			**0.9V**	
			-3	**-2/-2L**	**-1**	**-2L**	
$I_{CCBRAMQ}$	Quiescent V_{CCBRAM} supply current	XC7K70T	6	6	6	6	mA
		XC7K160T	14	14	14	14	mA
		XC7K325T	19	19	19	19	mA
		XC7K355T	31	31	31	31	mA
		XC7K410T	34	34	34	34	mA
		XC7K420T	41	41	41	41	mA
		XC7K480T	41	41	41	41	mA

Notes:

1. Typical values are specified at nominal voltage, 85°C junction temperatures (T_j) with single-ended SelectIO resources.
2. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
3. Use the XPower™ Estimator (XPE) spreadsheet tool (download at http://www.xilinx.com/power) to calculate static power consumption for conditions other than those specified.

Power-On/Off Power Supply Sequencing

The recommended power-on sequence is V_{CCINT}, V_{CCBRAM}, V_{CCAUX}, V_{CCAUX_IO}, and V_{CCO} to achieve minimum current draw and ensure that the I/Os are 3-stated at power-on. The recommended power-off sequence is the reverse of the power-on sequence. If V_{CCINT} and V_{CCBRAM} have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously. If V_{CCAUX}, V_{CCAUX_IO}, and V_{CCO} have the same recommended voltage levels then they can be powered by the same supply and ramped simultaneously.

For V_{CCO} voltages of 3.3V in HR I/O banks and configuration bank 0:

- The voltage difference between V_{CCO} and V_{CCAUX} must not exceed 2.625V for longer than $T_{VCCO2VCCAUX}$ for each power-on/off cycle to maintain device reliability levels.
- The $T_{VCCO2VCCAUX}$ time can be allocated in any percentage between the power-on and power-off ramps.

The recommended power-on sequence to achieve minimum current draw for the GTX transceivers is V_{CCINT}, $V_{MGTAVCC}$, $V_{MGTAVTT}$ OR $V_{MGTAVCC}$, V_{CCINT}, $V_{MGTAVTT}$. There is no recommended sequencing for $V_{MGTVCCAUX}$. Both $V_{MGTAVCC}$ and V_{CCINT} can be ramped simultaneously. The recommended power-off sequence is the reverse of the power-on sequence to achieve minimum current draw.

If these recommended sequences are not met, current drawn from $V_{MGTAVTT}$ can be higher than specifications during power-up and power-down.

- When $V_{MGTAVTT}$ is powered before $V_{MGTAVCC}$ and $V_{MGTAVTT} – V_{MGTAVCC} > 150$ mV and $V_{MGTAVCC} < 0.7$V, the $V_{MGTAVTT}$ current draw can increase by 460 mA per transceiver during $V_{MGTAVCC}$ ramp up. The duration of the current draw can be up to 0.3 x $T_{MGTAVCC}$ (ramp time from GND to 90% of $V_{MGTAVCC}$). The reverse is true for power-down.
- When $V_{MGTAVTT}$ is powered before V_{CCINT} and $V_{MGTAVTT} – V_{CCINT} > 150$ mV and $V_{CCINT} < 0.7$V, the $V_{MGTAVTT}$ current draw can increase by 50 mA per transceiver during V_{CCINT} ramp up. The duration of the current draw can be up to 0.3 x T_{VCCINT} (ramp time from GND to 90% of V_{CCINT}). The reverse is true for power-down.

LVDS DC Specifications (LVDS_25)

The LVDS_25 standard is available in the HR I/O banks. See UG471: *7 Series FPGAs SelectIO Resources User Guide* for more information.

Table 12: **LVDS_25 DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.375	2.500	2.625	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	0.700	–	–	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	R_T = 100 Ω across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	R_T = 100 Ω across Q and $\overline{Q}$ signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.300	1.200	1.425	V

LVDS DC Specifications (LVDS)

The LVDS standard is available in the HP I/O banks. See UG471: *7 Series FPGAs SelectIO Resources User Guide* for more information.

Table 13: **LVDS DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		1.710	1.800	1.890	V
V_{OH}	Output High Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	–	–	1.675	V
V_{OL}	Output Low Voltage for Q and $\overline{Q}$	R_T = 100 Ω across Q and $\overline{Q}$ signals	0.825	–	–	V
V_{ODIFF}	Differential Output Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	R_T = 100 Ω across Q and $\overline{Q}$ signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage	R_T = 100 Ω across Q and $\overline{Q}$ signals	1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage (Q – $\overline{Q}$), Q = High ($\overline{Q}$ – Q), $\overline{Q}$ = High	Common-mode input voltage = 1.25V	100	350	600	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ±350 mV	0.300	1.200	1.425	V

AC Switching Characteristics

All values represented in this data sheet are based on the speed specifications in ISE® software 14.3 v1.07 for the -3, -2, -2L(1.0V), -1, and v1.06 for -2L(0.9V) speed grades.

Switching characteristics are specified on a per-speed-grade basis and can be designated as Advance, Preliminary, or Production. Each designation is defined as follows:

Advance Product Specification

These specifications are based on simulations only and are typically available soon after device design specifications are frozen. Although speed grades with this designation are considered relatively stable and conservative, some under-reporting might still occur.

Preliminary Product Specification

These specifications are based on complete ES (engineering sample) silicon characterization. Devices and speed grades with this designation are intended to give a better indication of the expected performance of production silicon. The probability of under-reporting delays is greatly reduced as compared to Advance data.

Product Specification

These specifications are released once enough production silicon of a particular device family member has been characterized to provide full correlation between specifications and devices over numerous production lots. There is no under-reporting of delays, and customers receive formal notification of any subsequent changes. Typically, the slowest speed grades transition to production before faster speed grades.

Testing of AC Switching Characteristics

Internal timing parameters are derived from measuring internal test patterns. All AC switching characteristics are representative of worst-case supply voltage and junction temperature conditions.

For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer and back-annotate to the simulation net list. Unless otherwise noted, values apply to all Kintex-7 FPGAs.

Speed Grade Designations

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device. Table 14 correlates the current status of each Kintex-7 device on a per speed grade basis.

Table 14: **Kintex-7 Device Speed Grade Designations**

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC7K70T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K160T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K325T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K355T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K410T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K420T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)
XC7K480T			-3, -2, -2L(1.0V), -1, and -2L (0.9V)

Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

Table 15 lists the production released Kintex-7 device, speed grade, and the minimum corresponding supported speed specification version and ISE software revisions. The ISE software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 15: **Kintex-7 Device Production Software and Speed Specification Release**

Device	Speed Grade Designations			
	1.0V			0.9V
	-3	-2/-2L	-1	-2L
XC7K70T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K160T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K325T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K355T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K410T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K420T	ISE 14.2 v1.06			ISE 14.3 v1.06
XC7K480T	ISE 14.2 v1.06			ISE 14.3 v1.06

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Kintex-7 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the AC Switching Characteristics, page 11. In each table, the I/O bank type is either High Performance (HP) or High Range (HR).

Table 16: **Networking Applications Interface Performances**

Description	I/O Bank Type	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	HR	710	710	625	625	Mb/s
	HP	710	710	625	625	Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 14)	HR	1250	1250	950	950	Mb/s
	HP	1600	1400	1250	1250	Mb/s
SDR LVDS receiver (SFI-4.1)(1)	HR	710	710	625	625	Mb/s
	HP	710	710	625	625	Mb/s
DDR LVDS receiver (SPI-4.2)(1)	HR	1250	1250	950	950	Mb/s
	HP	1600	1400	1250	1250	Mb/s

Notes:

1. LVDS receivers are typically bounded with certain applications where specific dynamic phase-alignment (DPA) algorithms dominate deterministic performance.

Table 17: **Maximum Physical Interface (PHY) Rate for Memory Interfaces (FFG Packages)(1)(2)**

Memory Standard	I/O Bank Type	V_{CCAUX_IO}	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
4:1 Memory Controllers							
DDR3	HP	2.0V	1866	1866	1600	1333	Mb/s
	HP	1.8V	1600	1333	1066	1066	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1600	1600	1333	1066	Mb/s
	HP	1.8V	1333	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	800	800	800	Mb/s
RLDRAM III(3)	HP	2.0V	800	667	667	533	MHz
	HP	1.8V	550	500	450	450	MHz
	HR	N/A	N/A				
2:1 Memory Controllers							
DDR3	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V					
	HR	N/A					
QDR II+(4)	HP	2.0V	550	500	450	450	MHz
	HP	1.8V					
	HR	N/A	500	450	400	400	MHz
RLDRAM II	HP	2.0V	533	500	450	450	MHz
	HP	1.8V					
	HR	N/A					
LPDDR2(3)	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	667	667	667	Mb/s

Notes:

1. V_{REF} tracking is required. For more information, see UG586, *7 Series FPGAs Memory Interface Solutions User Guide*.
2. When using the internal V_{REF}, the maximum data rate is 800 Mb/s (400 MHz).
3. RLDRAM III (BL = 4, BL = 8) and LPDDR2 specifications have not been validated with memory IP.
4. The maximum QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations. Burst length 2 (BL = 2) implementations are limited to 333 MHz for all speed grades and I/O bank types.

Table 20: **1.8V IOB High Performance (HP) Switching Characteristics *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
LVCMOS12_F8	0.64	0.67	0.78	0.95	1.27	1.42	1.55	1.41	1.91	2.18	2.37	2.02	ns
LVDCI_18	0.47	0.50	0.60	0.86	1.99	2.15	2.35	2.44	2.62	2.91	3.17	3.05	ns
LVDCI_15	0.59	0.62	0.73	0.87	1.98	2.23	2.58	2.40	2.62	2.99	3.40	3.01	ns
LVDCI_DV2_18	0.47	0.50	0.60	0.87	1.99	2.15	2.34	1.86	2.62	2.90	3.17	2.48	ns
LVDCI_DV2_15	0.59	0.62	0.73	0.87	1.98	2.23	2.58	1.83	2.62	2.99	3.40	2.44	ns
HSLVDCI_18	0.68	0.72	0.82	0.86	1.99	2.15	2.35	2.43	2.62	2.91	3.17	3.04	ns
HSLVDCI_15	0.68	0.72	0.82	0.84	1.98	2.23	2.58	2.27	2.62	2.99	3.40	2.88	ns
SSTL18_I_S	0.68	0.72	0.82	0.86	1.02	1.15	1.24	1.41	1.66	1.90	2.07	2.02	ns
SSTL18_II_S	0.68	0.72	0.82	0.87	1.17	1.29	1.37	1.55	1.81	2.05	2.19	2.16	ns
SSTL18_I_DCI_S	0.68	0.72	0.82	0.76	0.92	1.06	1.17	1.32	1.56	1.82	1.99	1.93	ns
SSTL18_II_DCI_S	0.68	0.72	0.82	0.78	0.88	0.98	1.08	1.26	1.51	1.74	1.90	1.87	ns
SSTL18_II_T_DCI_S	0.68	0.72	0.82	0.78	0.92	1.06	1.17	1.32	1.56	1.82	1.99	1.93	ns
SSTL15_S	0.68	0.72	0.82	0.81	0.94	1.06	1.15	1.32	1.58	1.82	1.97	1.93	ns
SSTL15_DCI_S	0.68	0.72	0.82	0.78	0.94	1.06	1.15	1.30	1.57	1.82	1.97	1.91	ns
SSTL15_T_DCI_S	0.68	0.72	0.82	0.80	0.94	1.06	1.15	1.30	1.57	1.82	1.97	1.91	ns
SSTL135_S	0.69	0.72	0.82	0.89	0.97	1.10	1.19	1.35	1.60	1.85	2.01	1.96	ns
SSTL135_DCI_S	0.69	0.72	0.82	0.84	0.97	1.09	1.19	1.33	1.60	1.85	2.01	1.94	ns
SSTL135_T_DCI_S	0.69	0.72	0.82	0.84	0.97	1.09	1.19	1.33	1.60	1.85	2.01	1.94	ns
SSTL12_S	0.69	0.72	0.82	0.95	0.96	1.09	1.18	1.33	1.60	1.84	2.00	1.94	ns
SSTL12_DCI_S	0.69	0.72	0.82	0.91	1.03	1.17	1.27	1.33	1.66	1.92	2.09	1.94	ns
SSTL12_T_DCI_S	0.69	0.72	0.82	0.91	1.03	1.17	1.27	1.33	1.66	1.92	2.09	1.94	ns
DIFF_SSTL18_I_S	0.75	0.79	0.92	0.89	1.02	1.15	1.24	1.43	1.66	1.90	2.07	2.04	ns
DIFF_SSTL18_II_S	0.75	0.79	0.92	0.89	1.17	1.29	1.37	1.55	1.81	2.05	2.19	2.16	ns
DIFF_SSTL18_I_DCI_S	0.75	0.79	0.92	0.76	0.92	1.06	1.17	1.40	1.56	1.82	1.99	2.01	ns
DIFF_SSTL18_II_DCI_S	0.75	0.79	0.92	0.75	0.88	0.98	1.08	1.33	1.51	1.74	1.90	1.94	ns
DIFF_SSTL18_II_T_DCI_S	0.75	0.79	0.92	0.76	0.92	1.06	1.17	1.40	1.56	1.82	1.99	2.01	ns
DIFF_SSTL15_S	0.68	0.72	0.82	0.89	0.94	1.06	1.15	1.32	1.58	1.82	1.97	1.93	ns
DIFF_SSTL15_DCI_S	0.68	0.72	0.82	0.75	0.94	1.06	1.15	1.30	1.57	1.82	1.97	1.91	ns
DIFF_SSTL15_T_DCI_S	0.68	0.72	0.82	0.76	0.94	1.06	1.15	1.38	1.57	1.82	1.97	1.99	ns
DIFF_SSTL135_S	0.69	0.72	0.82	0.91	0.97	1.10	1.19	1.35	1.60	1.85	2.01	1.96	ns
DIFF_SSTL135_DCI_S	0.69	0.72	0.82	0.76	0.97	1.09	1.19	1.33	1.60	1.85	2.01	1.94	ns
DIFF_SSTL135_T_DCI_S	0.69	0.72	0.82	0.76	0.97	1.09	1.19	1.43	1.60	1.85	2.01	2.04	ns
DIFF_SSTL12_S	0.69	0.72	0.82	0.91	0.96	1.09	1.18	1.33	1.60	1.84	2.00	1.94	ns
DIFF_SSTL12_DCI_S	0.69	0.72	0.82	0.78	1.03	1.17	1.27	1.33	1.66	1.92	2.09	1.94	ns
DIFF_SSTL12_T_DCI_S	0.69	0.72	0.82	0.80	1.03	1.17	1.27	1.41	1.66	1.92	2.09	2.02	ns

Table 20: **1.8V IOB High Performance (HP) Switching Characteristics *(Cont'd)***

I/O Standard	T_{IOPI}				T_{IOOP}				T_{IOTP}				Units
	Speed Grade				Speed Grade				Speed Grade				
	1.0V			0.9V	1.0V			0.9V	1.0V			0.9V	
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	
SSTL18_I_F	0.68	0.72	0.82	0.86	0.94	1.06	1.15	1.32	1.58	1.82	1.97	1.93	ns
SSTL18_II_F	0.68	0.72	0.82	0.87	0.97	1.09	1.16	1.36	1.61	1.84	1.99	1.98	ns
SSTL18_I_DCI_F	0.68	0.72	0.82	0.76	0.89	1.02	1.10	1.30	1.53	1.77	1.92	1.91	ns
SSTL18_II_DCI_F	0.68	0.72	0.82	0.78	0.89	1.02	1.10	1.24	1.53	1.77	1.92	1.85	ns
SSTL18_II_T_DCI_F	0.68	0.72	0.82	0.78	0.89	1.02	1.10	1.27	1.53	1.77	1.92	1.88	ns
SSTL15_F	0.68	0.72	0.82	0.81	0.89	1.01	1.09	1.24	1.53	1.77	1.91	1.85	ns
SSTL15_DCI_F	0.68	0.72	0.82	0.78	0.89	1.01	1.09	1.27	1.53	1.77	1.91	1.88	ns
SSTL15_T_DCI_F	0.68	0.72	0.82	0.80	0.89	1.01	1.09	1.27	1.53	1.77	1.91	1.88	ns
SSTL135_F	0.69	0.72	0.82	0.89	0.88	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
SSTL135_DCI_F	0.69	0.72	0.82	0.84	0.89	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
SSTL135_T_DCI_F	0.69	0.72	0.82	0.84	0.89	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
SSTL12_F	0.69	0.72	0.82	0.95	0.88	1.00	1.08	1.26	1.52	1.76	1.90	1.87	ns
SSTL12_DCI_F	0.69	0.72	0.82	0.91	0.91	1.03	1.11	1.24	1.54	1.79	1.93	1.85	ns
SSTL12_T_DCI_F	0.69	0.72	0.82	0.91	0.91	1.03	1.11	1.26	1.54	1.79	1.93	1.87	ns
DIFF_SSTL18_I_F	0.75	0.79	0.92	0.89	0.94	1.06	1.15	1.38	1.58	1.82	1.97	1.99	ns
DIFF_SSTL18_II_F	0.75	0.79	0.92	0.89	0.97	1.09	1.16	1.40	1.61	1.84	1.99	2.01	ns
DIFF_SSTL18_I_DCI_F	0.75	0.79	0.92	0.76	0.89	1.02	1.10	1.36	1.53	1.77	1.92	1.98	ns
DIFF_SSTL18_II_DCI_F	0.75	0.79	0.92	0.75	0.89	1.02	1.10	1.32	1.53	1.77	1.92	1.93	ns
DIFF_SSTL18_II_T_DCI_F	0.75	0.79	0.92	0.76	0.89	1.02	1.10	1.38	1.53	1.77	1.92	1.99	ns
DIFF_SSTL15_F	0.68	0.72	0.82	0.89	0.89	1.01	1.09	1.24	1.53	1.77	1.91	1.85	ns
DIFF_SSTL15_DCI_F	0.68	0.72	0.82	0.75	0.89	1.01	1.09	1.27	1.53	1.77	1.91	1.88	ns
DIFF_SSTL15_T_DCI_F	0.68	0.72	0.82	0.76	0.89	1.01	1.09	1.35	1.53	1.77	1.91	1.96	ns
DIFF_SSTL135_F	0.69	0.72	0.82	0.91	0.88	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
DIFF_SSTL135_DCI_F	0.69	0.72	0.82	0.76	0.89	1.00	1.08	1.27	1.52	1.76	1.90	1.88	ns
DIFF_SSTL135_T_DCI_F	0.69	0.72	0.82	0.76	0.89	1.00	1.08	1.35	1.52	1.76	1.90	1.96	ns
DIFF_SSTL12_F	0.69	0.72	0.82	0.91	0.88	1.00	1.08	1.26	1.52	1.76	1.90	1.87	ns
DIFF_SSTL12_DCI_F	0.69	0.72	0.82	0.78	0.91	1.03	1.11	1.24	1.54	1.79	1.93	1.85	ns
DIFF_SSTL12_T_DCI_F	0.69	0.72	0.82	0.80	0.91	1.03	1.11	1.33	1.54	1.79	1.93	1.94	ns

Notes:

1. This I/O standard is only available in the 1.8V high-performance (HP) banks.

Input/Output Logic Switching Characteristics

Table 22: **ILOGIC Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup/Hold						
T_{ICE1CK}/T_{ICKCE1}	CE1 pin Setup/Hold with respect to CLK	0.42/0.00	0.48/0.00	0.67/0.00	0.56/–0.16	ns
T_{ISRCK}/T_{ICKSR}	SR pin Setup/Hold with respect to CLK	0.53/0.01	0.61/0.01	0.99/0.01	0.88/–0.30	ns
$T_{IDOCKE2}$/$T_{IOCKDE2}$	D pin Setup/Hold with respect to CLK without Delay (HP I/O banks only)	0.01/0.27	0.01/0.29	0.01/0.34	0.01/0.41	ns
$T_{IDOCKDE2}$/$T_{IOCKDDE2}$	DDLY pin Setup/Hold with respect to CLK (using IDELAY) (HP I/O banks only)	0.01/0.27	0.02/0.29	0.02/0.34	0.01/0.41	ns
$T_{IDOCKE3}$/$T_{IOCKDE3}$	D pin Setup/Hold with respect to CLK without Delay (HR I/O banks only)	0.01/0.27	0.01/0.29	0.01/0.34	0.01/0.41	ns
$T_{IDOCKDE3}$/$T_{IOCKDDE3}$	DDLY pin Setup/Hold with respect to CLK (using IDELAY) (HR I/O banks only)	0.01/0.27	0.02/0.29	0.02/0.34	0.01/0.41	ns
Combinatorial						
T_{IDIE2}	D pin to O pin propagation delay, no Delay (HP I/O banks only)	0.09	0.10	0.12	0.14	ns
T_{IDIDE2}	DDLY pin to O pin propagation delay (using IDELAY) (HP I/O banks only)	0.10	0.11	0.13	0.15	ns
T_{IDIE3}	D pin to O pin propagation delay, no Delay (HR I/O banks only)	0.09	0.10	0.12	0.14	ns
T_{IDIDE3}	DDLY pin to O pin propagation delay (using IDELAY) (HR I/O banks only)	0.10	0.11	0.13	0.15	ns
Sequential Delays						
T_{IDLOE2}	D pin to Q1 pin using flip-flop as a latch without Delay (HP I/O banks only)	0.36	0.39	0.45	0.54	ns
$T_{IDLODE2}$	DDLY pin to Q1 pin using flip-flop as a latch (using IDELAY) (HP I/O banks only)	0.36	0.39	0.45	0.55	ns
T_{IDLOE3}	D pin to Q1 pin using flip-flop as a latch without Delay (HR I/O banks only)	0.36	0.39	0.45	0.54	ns
$T_{IDLODE3}$	DDLY pin to Q1 pin using flip-flop as a latch (using IDELAY) (HR I/O banks only)	0.36	0.39	0.45	0.55	ns
T_{ICKQ}	CLK to Q outputs	0.47	0.50	0.58	0.71	ns
$T_{RQ\_ILOGICE2}$	SR pin to OQ/TQ out (HP I/O banks only)	0.84	0.94	1.16	1.32	ns
$T_{GSRQ\_ILOGICE2}$	Global Set/Reset to Q outputs (HP I/O banks only)	7.60	7.60	10.51	11.39	ns
$T_{RQ\_ILOGICE3}$	SR pin to OQ/TQ out (HR I/O banks only)	0.84	0.94	1.16	1.32	ns
$T_{GSRQ\_ILOGICE3}$	Global Set/Reset to Q outputs (HR I/O banks only)	7.60	7.60	10.51	11.39	ns
Set/Reset						
$T_{RPW\_ILOGICE2}$	Minimum Pulse Width, SR inputs (HP I/O banks only)	0.54	0.63	0.63	0.68	ns, Min
$T_{RPW\_ILOGICE3}$	Minimum Pulse Width, SR inputs (HR I/O banks only)	0.54	0.63	0.63	0.68	ns, Min

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 29: **CLB Distributed RAM Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T_{SHCKO}	Clock to A – B outputs	0.68	0.70	0.85	1.08	ns, Max
T_{SHCKO_1}	Clock to AMUX – BMUX outputs	0.91	0.95	1.15	1.44	ns, Max
Setup and Hold Times Before/After Clock CLK						
T_{DS_LRAM}/T_{DH_LRAM}	A – D inputs to CLK	0.45/0.23	0.45/0.24	0.54/0.27	0.69/0.33	ns, Min
T_{AS_LRAM}/T_{AH_LRAM}	Address An inputs to clock	0.13/0.50	0.14/0.50	0.17/0.58	0.21/0.63	ns, Min
	Address An inputs through MUXs and/or carry logic to clock	0.40/0.16	0.42/0.17	0.52/0.23	0.63/0.23	ns, Min
T_{WS_LRAM}/T_{WH_LRAM}	WE input to clock	0.29/0.09	0.30/0.09	0.36/0.09	0.46/0.10	ns, Min
T_{CECK_LRAM}/ T_{CKCE_LRAM}	CE input to CLK	0.29/0.09	0.30/0.09	0.37/0.09	0.47/0.10	ns, Min
Clock CLK						
T_{MPW}	Minimum pulse width	0.68	0.77	0.91	1.11	ns, Min
T_{MCP}	Minimum clock period	1.35	1.54	1.82	2.22	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 30: **CLB Shift Register Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Sequential Delays						
T_{REG}	Clock to A – D outputs	0.96	0.98	1.20	1.35	ns, Max
T_{REG_MUX}	Clock to AMUX – DMUX output	1.19	1.23	1.50	1.72	ns, Max
T_{REG_M31}	Clock to DMUX output via M31 output	0.89	0.91	1.10	1.25	ns, Max
Setup and Hold Times Before/After Clock CLK						
T_{WS_SHFREG}/ T_{WH_SHFREG}	WE input	0.26/0.09	0.27/0.09	0.33/0.09	0.41/0.10	ns, Min
T_{CECK_SHFREG}/ T_{CKCE_SHFREG}	CE input to CLK	0.27/0.09	0.28/0.09	0.33/0.09	0.42/0.10	ns, Min
T_{DS_SHFREG}/ T_{DH_SHFREG}	A – D inputs to CLK	0.28/0.26	0.28/0.26	0.33/0.30	0.41/0.36	ns, Min
Clock CLK						
T_{MPW_SHFREG}	Minimum pulse width	0.55	0.65	0.78	0.91	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time.

DSP48E1 Switching Characteristics

Table 32: **DSP48E1 Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Setup and Hold Times of Data/Control Pins to the Input Register Clock						
$T_{DSPDCK\_A\_AREG}$/ $T_{DSPCKD\_A\_AREG}$	A input to A register CLK	0.24/ 0.12	0.27/ 0.14	0.31/ 0.16	0.38/ 0.12	ns
$T_{DSPDCK\_B\_BREG}$/$T_{DSPCKD\_B\_BREG}$	B input to B register CLK	0.28/ 0.13	0.32/ 0.14	0.39/ 0.15	0.51/ 0.16	ns
$T_{DSPDCK\_C\_CREG}$/$T_{DSPCKD\_C\_CREG}$	C input to C register CLK	0.15/ 0.15	0.17/ 0.17	0.20/ 0.20	0.31/ 0.21	ns
$T_{DSPDCK\_D\_DREG}$/$T_{DSPCKD\_D\_DREG}$	D input to D register CLK	0.21/ 0.19	0.27/ 0.22	0.35/ 0.26	0.46/ 0.20	ns
$T_{DSPDCK\_ACIN\_AREG}$/$T_{DSPCKD\_ACIN\_AREG}$	ACIN input to A register CLK	0.21/ 0.12	0.24/ 0.14	0.27/ 0.16	0.31/ 0.12	ns
$T_{DSPDCK\_BCIN\_BREG}$/$T_{DSPCKD\_BCIN\_BREG}$	BCIN input to B register CLK	0.22/ 0.13	0.25/ 0.14	0.30/ 0.15	0.34/ 0.16	ns
Setup and Hold Times of Data Pins to the Pipeline Register Clock						
$T_{DSPDCK\_\{A, B\}\_MREG\_MULT}$/ $T_{DSPCKD\_B\_MREG\_MULT}$	{A, B,} input to M register CLK using multiplier	2.04/ –0.01	2.34/ –0.01	2.79/ –0.01	3.66/ –0.06	ns
$T_{DSPDCK\_\{A, B\}\_ADREG}$/ $T_{DSPCKD\_ D\_ADREG}$	{A, D} input to AD register CLK	1.09/ –0.02	1.25/ –0.02	1.49/ –0.02	1.94/ –0.23	ns
Setup and Hold Times of Data/Control Pins to the Output Register Clock						
$T_{DSPDCK\_\{A, B\}\_PREG\_MULT}$/ $T_{DSPCKD\_\{A, B\}\ \_PREG\_MULT}$	{A, B,} input to P register CLK using multiplier	3.41/ –0.24	3.90/ –0.24	4.64/ –0.24	5.89/ –0.41	ns
$T_{DSPDCK\_D\_PREG\_MULT}$/ $T_{DSPCKD\_D\_PREG\_MULT}$	D input to P register CLK using multiplier	3.33/ –0.62	3.81/ –0.62	4.53/ –0.62	5.70/ –1.42	ns
$T_{DSPDCK\_\{A, B\}\ \_PREG}$/ $T_{DSPCKD\_\{A, B\}\ \_PREG}$	A or B input to P register CLK not using multiplier	1.47/ –0.24	1.68/ –0.24	2.00/ –0.24	2.37/ –0.41	ns
$T_{DSPDCK\_C\_PREG}$/ $T_{DSPCKD\_C\_PREG}$	C input to P register CLK not using multiplier	1.30/ –0.22	1.49/ –0.22	1.78/ –0.22	2.11/ –0.36	ns
$T_{DSPDCK\_PCIN\_PREG}$/ $T_{DSPCKD\_PCIN\_PREG}$	PCIN input to P register CLK	1.12/ –0.13	1.28/ –0.13	1.52/ –0.13	1.81/ –0.21	ns
Setup and Hold Times of the CE Pins						
$T_{DSPDCK\_\{CEA;CEB\}\_\{AREG;BREG\}}$/ $T_{DSPCKD\_\{CEA;CEB\}\_\{AREG;BREG\}}$	{CEA; CEB} input to {A; B} register CLK	0.30/ 0.05	0.36/ 0.06	0.44/ 0.09	0.55/ 0.09	ns
$T_{DSPDCK\_CEC\_CREG}$/ $T_{DSPCKD\_CEC\_CREG}$	CEC input to C register CLK	0.24/ 0.08	0.29/ 0.09	0.36/ 0.11	0.43/ 0.11	ns
$T_{DSPDCK\_CED\_DREG}$/ $T_{DSPCKD\_CED\_DREG}$	CED input to D register CLK	0.31/ –0.02	0.36/ –0.02	0.44/ –0.02	0.58/ 0.12	ns
$T_{DSPDCK\_CEM\_MREG}$/ $T_{DSPCKD\_CEM\_MREG}$	CEM input to M register CLK	0.26/ 0.15	0.29/ 0.17	0.33/ 0.20	0.39/ 0.25	ns
$T_{DSPDCK\_CEP\_PREG}$/ $T_{DSPCKD\_CEP\_PREG}$	CEP input to P register CLK	0.31/ 0.01	0.36/ 0.01	0.45/ 0.01	0.54/ 0.00	ns

Table 32: **DSP48E1 Switching Characteristics *(Cont'd)***

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Clock to Outs from Pipeline Register Clock to Output Pins						
$T_{DSPCKO\_P\_MREG}$	CLK MREG to P output	1.42	1.64	1.96	2.31	ns
$T_{DSPCKO\_CARRYCASCOUT\_MREG}$	CLK MREG to CARRYCASCOUT output	1.63	1.87	2.24	2.65	ns
$T_{DSPCKO\_P\_ADREG\_MULT}$	CLK ADREG to P output using multiplier	2.30	2.63	3.13	3.90	ns
$T_{DSPCKO\_CARRYCASCOUT\_ADREG\_MULT}$	CLK ADREG to CARRYCASCOUT output using multiplier	2.51	2.87	3.41	4.23	ns
Clock to Outs from Input Register Clock to Output Pins						
$T_{DSPCKO\_P\_AREG\_MULT}$	CLK AREG to P output using multiplier	3.34	3.83	4.55	5.80	ns
$T_{DSPCKO\_P\_BREG}$	CLK BREG to P output not using multiplier	1.39	1.59	1.88	2.24	ns
$T_{DSPCKO\_P\_CREG}$	CLK CREG to P output not using multiplier	1.43	1.64	1.95	2.32	ns
$T_{DSPCKO\_P\_DREG\_MULT}$	CLK DREG to P output using multiplier	3.32	3.80	4.51	5.74	ns
Clock to Outs from Input Register Clock to Cascading Output Pins						
$T_{DSPCKO\_\{ACOUT;\ BCOUT\}\_\{AREG;\ BREG\}}$	CLK (ACOUT, BCOUT) to {A,B} register output	0.55	0.62	0.74	0.87	ns
$T_{DSPCKO\_CARRYCASCOUT\_\{AREG,\ BREG\}\_MULT}$	CLK (AREG, BREG) to CARRYCASCOUT output using multiplier	3.55	4.06	4.84	6.13	ns
$T_{DSPCKO\_CARRYCASCOUT\_\ BREG}$	CLK BREG to CARRYCASCOUT output not using multiplier	1.60	1.82	2.16	2.58	ns
$T_{DSPCKO\_CARRYCASCOUT\_\ DREG\_MULT}$	CLK DREG to CARRYCASCOUT output using multiplier	3.52	4.03	4.79	6.07	ns
$T_{DSPCKO\_CARRYCASCOUT\_\ CREG}$	CLK CREG to CARRYCASCOUT output	1.64	1.88	2.23	2.65	ns
Maximum Frequency						
F_{MAX}	With all registers used	741.84	650.20	547.95	429.37	MHz
F_{MAX_PATDET}	With pattern detector	627.35	549.75	463.61	365.90	MHz
$F_{MAX\_MULT\_NOMREG}$	Two register multiply without MREG	412.20	360.75	303.77	248.32	MHz
$F_{MAX\_MULT\_NOMREG\_PATDET}$	Two register multiply without MREG with pattern detect	374.25	327.65	276.01	225.73	MHz
$F_{MAX\_PREADD\_MULT\_NOADREG}$	Without ADREG	468.82	408.66	342.70	263.44	MHz
$F_{MAX\_PREADD\_MULT\_NOADREG\_PATDET}$	Without ADREG with pattern detect	468.82	408.66	342.70	263.44	MHz
$F_{MAX\_NOPIPELINEREG}$	Without pipeline registers (MREG, ADREG)	306.84	267.81	225.02	177.15	MHz
$F_{MAX\_NOPIPELINEREG\_PATDET}$	Without pipeline registers (MREG, ADREG) with pattern detect	285.23	249.13	209.38	165.32	MHz

MMCM Switching Characteristics

Table 38: **MMCM Specification**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
MMCM_F_{INMAX}	Maximum Input Clock Frequency	1066.00	933.00	800.00	800.00	MHz
MMCM_F_{INMIN}	Minimum Input Clock Frequency	10.00	10.00	10.00	10.00	MHz
MMCM_$F_{INJITTER}$	Maximum Input Clock Period Jitter	< 20% of clock input period or 1 ns Max				
MMCM_F_{INDUTY}	Allowable Input Duty Cycle: 10—49 MHz	25.00	25.00	25.00	25.00	%
	Allowable Input Duty Cycle: 50—199 MHz	30.00	30.00	30.00	30.00	%
	Allowable Input Duty Cycle: 200—399 MHz	35.00	35.00	35.00	35.00	%
	Allowable Input Duty Cycle: 400—499 MHz	40.00	40.00	40.00	40.00	%
	Allowable Input Duty Cycle: >500 MHz	45.00	45.00	45.00	45.00	%
MMCM_F_{MIN_PSCLK}	Minimum Dynamic Phase Shift Clock Frequency	0.01	0.01	0.01	0.01	MHz
MMCM_F_{MAX_PSCLK}	Maximum Dynamic Phase Shift Clock Frequency	550.00	500.00	450.00	450.00	MHz
MMCM_F_{VCOMIN}	Minimum MMCM VCO Frequency	600.00	600.00	600.00	600.00	MHz
MMCM_F_{VCOMAX}	Maximum MMCM VCO Frequency	1600.00	1440.00	1200.00	1200.00	MHz
MMCM_$F_{BANDWIDTH}$	Low MMCM Bandwidth at Typical(1)	1.00	1.00	1.00	1.00	MHz
	High MMCM Bandwidth at Typical(1)	4.00	4.00	4.00	4.00	MHz
MMCM_$T_{STATPHAOFFSET}$	Static Phase Offset of the MMCM Outputs(2)	0.12	0.12	0.12	0.12	ns
MMCM_$T_{OUTJITTER}$	MMCM Output Jitter	Note 3				
MMCM_$T_{OUTDUTY}$	MMCM Output Clock Duty Cycle Precision(4)	0.20	0.20	0.20	0.25	ns
MMCM_$T_{LOCKMAX}$	MMCM Maximum Lock Time	100.00	100.00	100.00	100.00	µs
MMCM_F_{OUTMAX}	MMCM Maximum Output Frequency	1066.00	933.00	800.00	800.00	MHz
MMCM_F_{OUTMIN}	MMCM Minimum Output Frequency(5)(6)	4.69	4.69	4.69	4.69	MHz
MMCM_$T_{EXTFDVAR}$	External Clock Feedback Variation	< 20% of clock input period or 1 ns Max				
MMCM_$RST_{MINPULSE}$	Minimum Reset Pulse Width	5.00	5.00	5.00	5.00	ns
MMCM_F_{PFDMAX}	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to High or Optimized	550.00	500.00	450.00	450.00	MHz
	Maximum Frequency at the Phase Frequency Detector with Bandwidth Set to Low	300.00	300.00	300.00	300.00	MHz
MMCM_F_{PFDMIN}	Minimum Frequency at the Phase Frequency Detector	10.00	10.00	10.00	10.00	MHz
MMCM_$T_{FBDELAY}$	Maximum Delay in the Feedback Path	3 ns Max or one CLKIN cycle				
MMCM Switching Characteristics Setup and Hold						
$T_{MMCMDCK\_PSEN}$/ $T_{MMCMCKD\_PSEN}$	Setup and Hold of Phase Shift Enable	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
$T_{MMCMDCK\_PSINCDEC}$/ $T_{MMCMCKD\_PSINCDEC}$	Setup and Hold of Phase Shift Increment/Decrement	1.04/0.00	1.04/0.00	1.04/0.00	1.04/0.00	ns
$T_{MMCMCKO\_PSDONE}$	Phase Shift Clock-to-Out of PSDONE	0.59	0.68	0.81	0.78	ns
Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK						
$T_{MMCMDCK\_DADDR}$/ $T_{MMCMCKD\_DADDR}$	DADDR Setup/Hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min
$T_{MMCMDCK\_DI}$/ $T_{MMCMCKD\_DI}$	DI Setup/Hold	1.25/0.15	1.40/0.15	1.63/0.15	1.43/0.00	ns, Min

Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

Table 45: **Global Clock Input Setup and Hold Without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks**

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard.(1)							
T_{PSFD}/ T_{PHFD}	Full Delay (Legacy Delay or Default Delay) Global Clock Input and IFF(2) without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks	XC7K70T	2.83/–0.29	2.95/–0.29	3.15/–0.29	4.96/–0.33	ns
		XC7K160T	3.17/–0.35	3.29/–0.35	3.55/–0.35	5.54/–0.49	ns
		XC7K325T	2.83/–0.06	2.94/–0.06	3.15/–0.06	5.18/–0.14	ns
		XC7K355T	3.26/–0.32	3.41/–0.32	3.67/–0.32	5.84/–0.49	ns
		XC7K410T	3.43/–0.34	3.59/–0.34	3.88/–0.34	6.21/–0.54	ns
		XC7K420T	3.37/–0.27	3.48/–0.27	3.76/–0.27	6.00/–0.52	ns
		XC7K480T	3.37/–0.27	3.48/–0.27	3.76/–0.27	6.00/–0.52	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.

Table 46: **Clock-Capable Clock Input Setup and Hold With MMCM**

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard.(1)							
$T_{PSMMCMCC}$/ $T_{PHMMCMCC}$	No Delay clock-capable clock input and IFF(2) with MMCM	XC7K70T	2.39/–0.22	2.65/–0.22	2.94/–0.22	2.21/–0.44	ns
		XC7K160T	2.49/–0.20	2.77/–0.20	3.07/–0.20	2.38/–0.47	ns
		XC7K325T	2.55/–0.16	2.85/–0.16	3.14/–0.16	2.60/–0.47	ns
		XC7K355T	2.43/–0.16	2.73/–0.16	3.00/–0.16	2.47/–0.43	ns
		XC7K410T	2.55/–0.16	2.84/–0.16	3.14/–0.16	2.58/–0.47	ns
		XC7K420T	2.47/–0.09	2.73/–0.09	3.02/–0.09	2.40/–0.41	ns
		XC7K480T	2.47/–0.09	2.73/–0.09	3.02/–0.09	2.40/–0.41	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 47: Clock-Capable Clock Input Setup and Hold With PLL

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to Clock-Capable Clock Input Signal for SSTL15 Standard.(1)							
$T_{PSPLLCC}$/ $T_{PHPLLCC}$	No Delay clock-capable clock input and IFF(2) with PLL	XC7K70T	2.75/–0.32	3.04/–0.32	3.33/–0.32	2.42/–0.54	ns
		XC7K160T	2.85/–0.31	3.16/–0.31	3.46/–0.31	2.59/–0.56	ns
		XC7K325T	2.91/–0.27	3.24/–0.27	3.54/–0.27	2.80/–0.56	ns
		XC7K355T	2.79/–0.27	3.12/–0.27	3.40/–0.27	2.67/–0.52	ns
		XC7K410T	2.91/–0.27	3.24/–0.27	3.53/–0.27	2.78/–0.56	ns
		XC7K420T	2.83/–0.20	3.12/–0.20	3.41/–0.20	2.61/–0.50	ns
		XC7K480T	2.83/–0.20	3.12/–0.20	3.41/–0.20	2.61/–0.50	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 48: Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIO

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to a Forwarded Clock Input Pin Using BUFIO for SSTL15 Standard.						
T_{PSCS}/T_{PHCS}	Setup/Hold of I/O clock for HR I/O banks	–0.36/1.36	–0.36/1.50	–0.36/1.70	–0.44/1.87	ns
	Setup/Hold of I/O clock for HP I/O banks	–0.34/1.39	–0.34/1.53	–0.34/1.73	–0.44/1.87	ns

Table 49: Sample Window

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
T_{SAMP}	Sampling Error at Receiver Pins(1)	0.51	0.56	0.61	0.56	ns
T_{SAMP_BUFIO}	Sampling Error at Receiver Pins using BUFIO(2)	0.30	0.35	0.40	0.35	ns

Notes:

1. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
   - CLK0 MMCM jitter
   - MMCM accuracy (phase offset)
   - MMCM phase shift resolution

   These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIO clock network and IDELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

GTX Transceiver Specifications

GTX Transceiver DC Input and Output Levels

Table 51 summarizes the DC output specifications of the GTX transceivers in Kintex-7 FPGAs. Consult UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide* for further details.

Table 51: **GTX Transceiver DC Specifications**

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
DV_{PPOUT}	Differential peak-to-peak output voltage[1]	Transmitter output swing is set to maximum setting	–	–	1000	mV
$V_{CMOUTDC}$	DC common mode output voltage.	Equation based	$V_{MGTAVTT} – DV_{PPOUT}/4$			mV
R_{OUT}	Differential output resistance		–	100	–	Ω
T_{OSKEW}	Transmitter output pair (TXP and TXN) intra-pair skew		–	2	12	ps
DV_{PPIN}	Differential peak-to-peak input voltage (external AC coupled)	>10.3125 Gb/s	150	–	1250	mV
		6.6 Gb/s to 10.3125 Gb/s	150	–	1250	mV
		≤ 6.6 Gb/s	150	–	2000	mV
V_{IN}	Absolute input voltage	DC coupled $V_{MGTAVTT}$ = 1.2V	–200	–	$V_{MGTAVTT}$	mV
V_{CMIN}	Common mode input voltage	DC coupled $V_{MGTAVTT}$ = 1.2V	–	2/3 $V_{MGTAVTT}$	–	mV
R_{IN}	Differential input resistance		–	100	–	Ω
C_{EXT}	Recommended external AC coupling capacitor[2]		–	100	–	nF

Notes:

1. The output swing and preemphasis levels are programmable using the attributes discussed in UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide* and can result in values lower than reported in this table.
2. Other values can be used as appropriate to conform to specific protocols and standards.

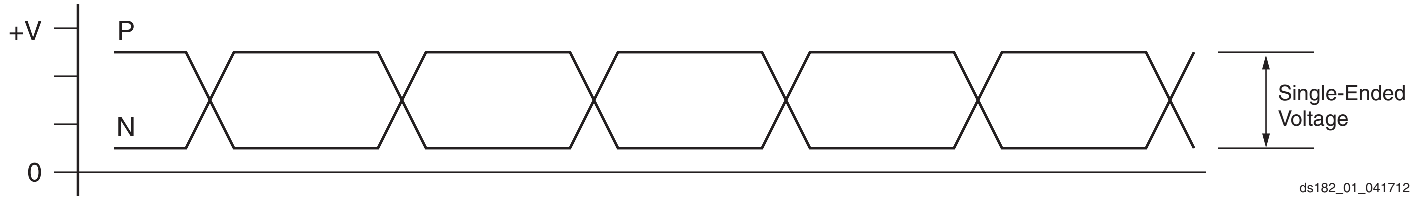

Figure 1: **Single-Ended Peak-to-Peak Voltage**

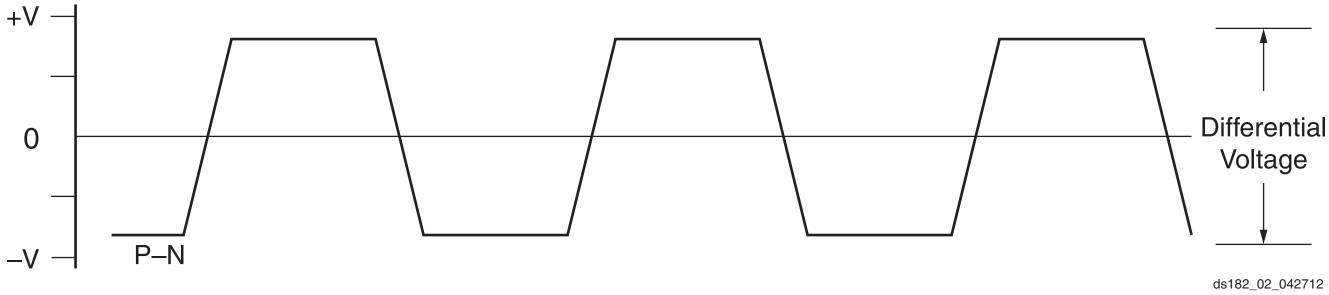

Figure 2: **Differential Peak-to-Peak Voltage**

Table 52 summarizes the DC specifications of the clock input of the GTX transceiver. Consult UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide* for further details.

Table 52: **GTX Transceiver Clock DC Input Level Specification**

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	250	–	2000	mV
R_{IN}	Differential input resistance	–	100	–	Ω
C_{EXT}	Required external AC coupling capacitor	–	100	–	nF

GTX Transceiver Switching Characteristics

Consult UG476: *7 Series FPGAs GTX/GTH Transceiver User Guide* for further information.

Table 53: **GTX Transceiver Performance**

Symbol	Description	Output Divider	Speed Grade								Units
			1.0V						0.9V		
			-3		-2/-2L		-1(1)		-2L(2)		
			Package Type								
			FF	FB	FF	FB	FF	FB	FF	FB	
F_{GTXMAX}(3)	Maximum GTX transceiver data rate		12.5	6.6	10.3125	6.6	8.0	6.6	6.6	6.6	Gb/s
F_{GTXMIN}(3)	Minimum GTX transceiver data rate		0.500	0.500	0.500	0.500	0.500	0.500	0.500	0.500	Gb/s
$F_{GTXCRANGE}$	CPLL line rate range	1	3.2–6.6								Gb/s
		2	1.6–3.3								Gb/s
		4	0.8–1.65								Gb/s
		8	0.5–0.825								Gb/s
		16	N/A								Gb/s
$F_{GTXQRANGE1}$	QPLL line rate range 1	1	5.93–8.0	5.93–6.6	5.93–8.0	5.93–6.6	5.93–8.0	5.93–6.6	5.93–6.6		Gb/s
		2	2.965–4.0		2.965–4.0		2.965–4.0		2.965–3.3		Gb/s
		4	1.4825–2.0		1.4825–2.0		1.4825–2.0		1.4825–1.65		Gb/s
		8	0.74125–1.0		0.74125–1.0		0.74125–1.0		0.74125–0.825		Gb/s
		16	N/A		N/A		N/A		N/A		Gb/s
$F_{GTXQRANGE2}$	QPLL line rate range 2(4)	1	9.8–12.5	N/A	9.8–10.3125	N/A	N/A		N/A		Gb/s
		2	4.9–6.25		4.9–5.15625		N/A		N/A		Gb/s
		4	2.45–3.125		2.45–2.578125		N/A		N/A		Gb/s
		8	1.225–1.5625		1.225–1.2890625		N/A		N/A		Gb/s
		16	0.6125–0.78125		0.6125–0.64453125		N/A		N/A		Gb/s
$F_{GCPLLRANGE}$	GTX transceiver CPLL frequency range		1.6–3.3		1.6–3.3		1.6–3.3		1.6–3.3		GHz
$F_{GQPLLRANGE1}$	GTX transceiver QPLL frequency range 1		5.93–8.0		5.93–8.0		5.93–8.0		5.93–6.6		GHz

Table 59: **GTX Transceiver Receiver Switching Characteristics**

Symbol	Description		Min	Typ	Max	Units
F_{GTXRX}	Serial data rate	RX oversampler not enabled	0.500	–	F_{GTXMAX}	Gb/s
$T_{RXELECIDLE}$	Time for RXELECIDLE to respond to loss or restoration of data		–	10	–	ns
$RX_{OOBVDPP}$	OOB detect threshold peak-to-peak		60	–	150	mV
RX_{SST}	Receiver spread-spectrum tracking(1)	Modulated @ 33 KHz	–5000	–	0	ppm
RX_{RL}	Run length (CID)		–	–	512	UI
RX_{PPMTOL}	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	–1250	–	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	–700	–	700	ppm
		Bit rates > 8.0 Gb/s	–200	–	200	ppm
SJ Jitter Tolerance(2)						
JT_SJ$_{12.5}$	Sinusoidal Jitter (QPLL)(3)	12.5 Gb/s	0.3	–	–	UI
JT_SJ$_{11.18}$	Sinusoidal Jitter (QPLL)(3)	11.18 Gb/s	0.3	–	–	UI
JT_SJ$_{10.32}$	Sinusoidal Jitter (QPLL)(3)	10.32 Gb/s	0.3	–	–	UI
JT_SJ$_{9.95}$	Sinusoidal Jitter (QPLL)(3)	9.95 Gb/s	0.3	–	–	UI
JT_SJ$_{9.8}$	Sinusoidal Jitter (QPLL)(3)	9.8 Gb/s	0.3	–	–	UI
JT_SJ$_{8.0}$	Sinusoidal Jitter (QPLL)(3)	8.0 Gb/s	0.44	–	–	UI
JT_SJ$_{6.6\_QPLL}$	Sinusoidal Jitter (QPLL)(3)	6.6 Gb/s	0.48	–	–	UI
JT_SJ$_{6.6\_CPLL}$	Sinusoidal Jitter (CPLL)(3)	6.6 Gb/s	0.44	–	–	UI
JT_SJ$_{5.0}$	Sinusoidal Jitter (CPLL)(3)	5.0 Gb/s	0.44	–	–	UI
JT_SJ$_{4.25}$	Sinusoidal Jitter (CPLL)(3)	4.25 Gb/s	0.44	–	–	UI
JT_SJ$_{3.75}$	Sinusoidal Jitter (CPLL)(3)	3.75 Gb/s	0.44	–	–	UI
JT_SJ$_{3.2}$	Sinusoidal Jitter (CPLL)(3)	3.2 Gb/s(4)	0.45	–	–	UI
JT_SJ$_{3.2L}$	Sinusoidal Jitter (CPLL)(3)	3.2 Gb/s(5)	0.45	–	–	UI
JT_SJ$_{2.5}$	Sinusoidal Jitter (CPLL)(3)	2.5 Gb/s(6)	0.5	–	–	UI
JT_SJ$_{1.25}$	Sinusoidal Jitter (CPLL)(3)	1.25 Gb/s(7)	0.5	–	–	UI
JT_SJ$_{500}$	Sinusoidal Jitter (CPLL)(3)	500 Mb/s	0.4	–	–	UI
SJ Jitter Tolerance with Stressed Eye(2)						
JT_TJSE$_{3.2}$	Total Jitter with Stressed Eye(8)	3.2 Gb/s	0.70	–	–	UI
JT_TJSE$_{6.6}$		6.6 Gb/s	0.70	–	–	UI
JT_SJSE$_{3.2}$	Sinusoidal Jitter with Stressed Eye(8)	3.2 Gb/s	0.1	–	–	UI
JT_SJSE$_{6.6}$		6.6 Gb/s	0.1	–	–	UI

Notes:

1. Using RXOUT_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of 1e^{-12}.
3. The frequency of the injected sinusoidal jitter is 10 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
5. CPLL frequency at 1.6 GHz and RXOUT_DIV = 1.
6. CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
7. CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
8. Composite jitter with RX and LPM or DFE mode.

Table 63: CEI-6G and CEI-11G Protocol Characteristics

Description	Line Rate (Mb/s)	Interface	Min	Max	Units
CEI-6G Transmitter Jitter Generation					
Total transmitter jitter[1]	4976–6375	CEI-6G-SR	–	0.3	UI
		CEI-6G-LR	–	0.3	UI
CEI-6G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance[1]	4976–6375	CEI-6G-SR	0.6	–	UI
		CEI-6G-LR	0.95	–	UI
CEI-11G Transmitter Jitter Generation					
Total transmitter jitter[2]	9950–11100	CEI-11G-SR	–	0.3	UI
		CEI-11G-LR/MR	–	0.3	UI
CEI-11G Receiver High Frequency Jitter Tolerance					
Total receiver jitter tolerance[2]	9950–11100	CEI-11G-SR	0.65	–	UI
		CEI-11G-MR	0.65	–	UI
		CEI-11G-LR	0.825	–	UI

Notes:

1. Tested at most commonly used line rate of 6250 Mb/s using 390.625 MHz reference clock.
2. Tested at line rate of 9950 Mb/s using 155.46875 MHz reference clock and 11100 Mb/s using 173.4375 MHz reference clock.

Table 64: SFP+ Protocol Characteristics

Description	Line Rate (Mb/s)	Min	Max	Units
SFP+ Transmitter Jitter Generation				
Total transmitter jitter	9830.40[1]	–	0.28	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			
SFP+ Receiver Frequency Jitter Tolerance				
Total receiver jitter tolerance	9830.40[1]	0.7	–	UI
	9953.00			
	10312.50			
	10518.75			
	11100.00			

Notes:

1. Line rated used for CPRI over SFP+ applications.

Revision History

The following table shows the revision history for this document:

Date	Version	Description
03/01/11	1.0	Initial Xilinx release.
04/01/11	1.1	Added the XC7K355T, XC7K420T, and XC7K480T devices throughout data sheet. Added the extended temperature range discussion to page 1. Updated V_{CCAUX_IO} in Table 2. Edits to clarify Power-On/Off Power Supply Sequencing power sequencing discussion. Added I_{CCAUX_IO} and I_{CCBRAM} to Table 6 and Table 7. Updated MMCM_F_{INDUTY} and added $F_{INJITTER}$, $T_{OUTJITTER}$, $T_{EXTFDVAR}$, and Note 3 to Table 38. Removed the SBG324 package from Table 50. Updated the Notice of Disclaimer.
10/04/11	1.2	Replaced -1L with -2L throughout this data sheet. Updated Min/Max values and removed Note 5 from Table 2. Clarified Power-On/Off Power Supply Sequencing power sequencing discussion including adding $T_{VCCO2VCCAUX}$ to Table 8. Updated V_{ICM} in Table 12 and Table 13. Added Note 1 to table 12. Updated Table 69 including adding Note 1. Added *Absolute Maximum Ratings for GTX Transceivers*. Revised the reference clock maximum frequency (F_{GCLK}) in Table 55. Added Table 57. Added LVTTL and removed SSTL135_II and SSTL15_II specifications from Table 19. Removed HSTL_III from Table 20. Removed the *I/O Standard Adjustment Measurement Methodology* section. Use IBIS for more accurate information and measurements. Updated $T_{IDELAYPAT\_JIT}$ in Table 26. Added T_{AS}/T_{AH} to Table 28. Added $T_{RDCK\_DI\_WF\_NC}$/$T_{RCKD\_DI\_WF\_NC}$ and $T_{RDCK\_DI\_RF}$/$T_{RCKD\_DI\_RF}$ to Table 31. Completely updated Table 68. Updated the AC Switching Characteristics in Table 19, Table 20, Table 21, Table 22, Table 23, Table 24, Table 26 through Table 38, Table 40 though Table 37, and Table 67.
11/03/11	1.3	Revised the V_{OCM} specification in Table 12. Updated the AC Switching Characteristics based upon the ISE 13.3 v1.02 speed specification throughout document including Table 19 and Table 20. Added MMCM_$T_{FBDELAY}$ while adding MMCM_ to the symbol names of a few specifications in Table 38 and PLL to the symbol names in Table 39. In Table 40 through Table 47, updated the pin-to-pin descriptions with the SSTL15 standard. Updated units in Table 49.
02/13/12	1.4	Updated summary description on page 1. In Table 2, revised V_{CCO} for the 3.3V HR I/O banks and updated T_j. Added typical values to Table 3. Updated the notes in Table 6. Added MGTAVCC, MGTAVTT, and MGTVCCAUX power supply ramp times to Table 8. Rearranged Table 9, added Mobile_DDR, HSTL_I_18, HSTL_II_18, HSUL_12, SSTL135_R, SSTL15_R, and SSTL12 and removed DIFF_SSTL135, DIFF_SSTL18_I, DIFF_SSTL18_II, DIFF_HSTL_I, and DIFF_HSTL_II. Added Table 10 and Table 11. Revised the specifications in Table 12 and Table 13. Updated the eFUSE Programming Conditions section and removed the endurance table. Added the IO_FIFO Switching Characteristics table. Revised I_{CCADC} and updated Note 1 in Table 67. Revised DDR LVDS transmitter data width in Table 16. Updated the AC Switching Characteristics based upon the ISE 13.4 v1.03 speed specification throughout document. Removed notes from Table 28 as they are no longer applicable. Updated specifications in Table 68. Updated Note 1 in Table 37. In the GTX Transceiver DC Input and Output Levels section: Revised V_{IN}, and added I_{DCIN} and I_{DCOUT} to Table 51. Added Note 4 to Table 53. In Table 55, revised F_{GCLK}, removed T_{PHASE}, and added T_{DLOCK}. Revised specifications and added Note 2 to Table 57. Added Table 58 and Table 59 along with GTX Transceiver Protocol Jitter Characteristics in Table 60 through Table 65.
05/23/12	1.5	Reorganized entire data sheet including adding Table 44 and Table 48. Updated T_{SOL} in Table 1. Updated I_{BATT} and added R_{IN_TERM} to Table 3. Added values to Table 6 and Table 7. Updated Power-On/Off Power Supply Sequencing, page 6 with regards to GTX transceivers. Updated many parameters in Table 9 including SSTL135 and SSTL135_R. Removed V_{OX} column and added DIFF_HSUL_12 to Table 11. Updated V_{OL} in Table 12. Updated Table 16 and removed notes 2 and 3. Updated Table 17. Updated the AC Switching Characteristics based upon the ISE 14.1 v1.04 for the -3, -2, -2L (1.0V), -1, and -2L (0.9V) speed specifications throughout the document. In Table 31, updated Reset Delays section including Note 10 and Note 11. Added data for T_{LOCK} and T_{DLOCK} in Table 55. Updated many of the XADC specifications in Table 67 and added Note 2. Updated and moved *Dynamic Reconfiguration Port (DRP) for MMCM Before and After DCLK* section from Table 68 to Table 38 and Table 39.